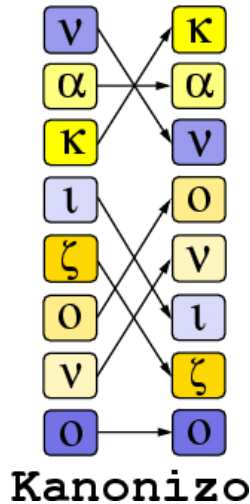




# Towards the Prioritization of Regression Test Suites with Data Flow Information



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## Definitions

- **Test Case** – An individual unit test
- **Test Suite** – A tuple of test cases
- **Regression Testing** – Testing that occurs after the completion of development or maintenance activities when a test suite comprised of all accumulated unit tests is executed
- **Test Prioritization** – The process of arranging test cases in a given test suite to facilitate the detection of defects earlier in the execution of the test suite

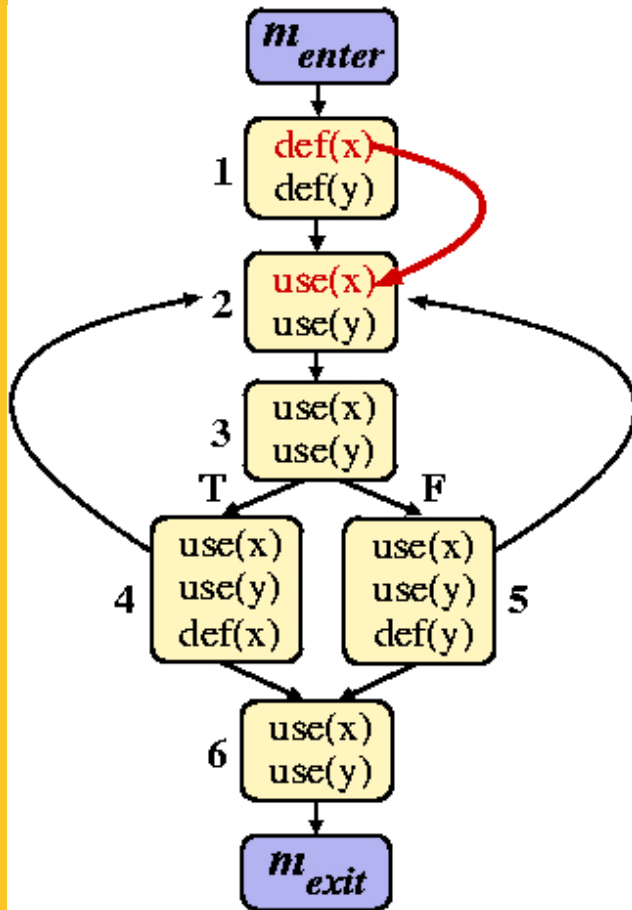


## Motivation

- Regression testing may account for as much as one-half the cost of software maintenance
- Prioritization is often more feasible than test selection
- Tests that fulfill the *all-DUs* test adequacy criteria are more likely to reveal defects than those that satisfy control flow based criteria



# Dataflow



- Model each method in a program as a control flow graph
- Control flow family of test criteria (ex: *all-nodes*, *all edges*, *all-paths*)
- Data flow criteria evolved from control flow (ex: *all-DUs*, *all-P-Uses*, *all-C-Uses*)
- Focus on intraprocedural def-use associations



## Metrics

- *APFD* – The rate of fault detection per percentage of test suite execution

$$APFD(T, P) = 1 - \frac{\sum_{i=1}^g reveal(i, T)}{rg} + \frac{1}{2r}$$

- *PTR* – Percentage of a given test suite that must be executed for all faults to be detected

$$PTR(T, P) = \frac{r_g}{r}$$



## Metrics Example

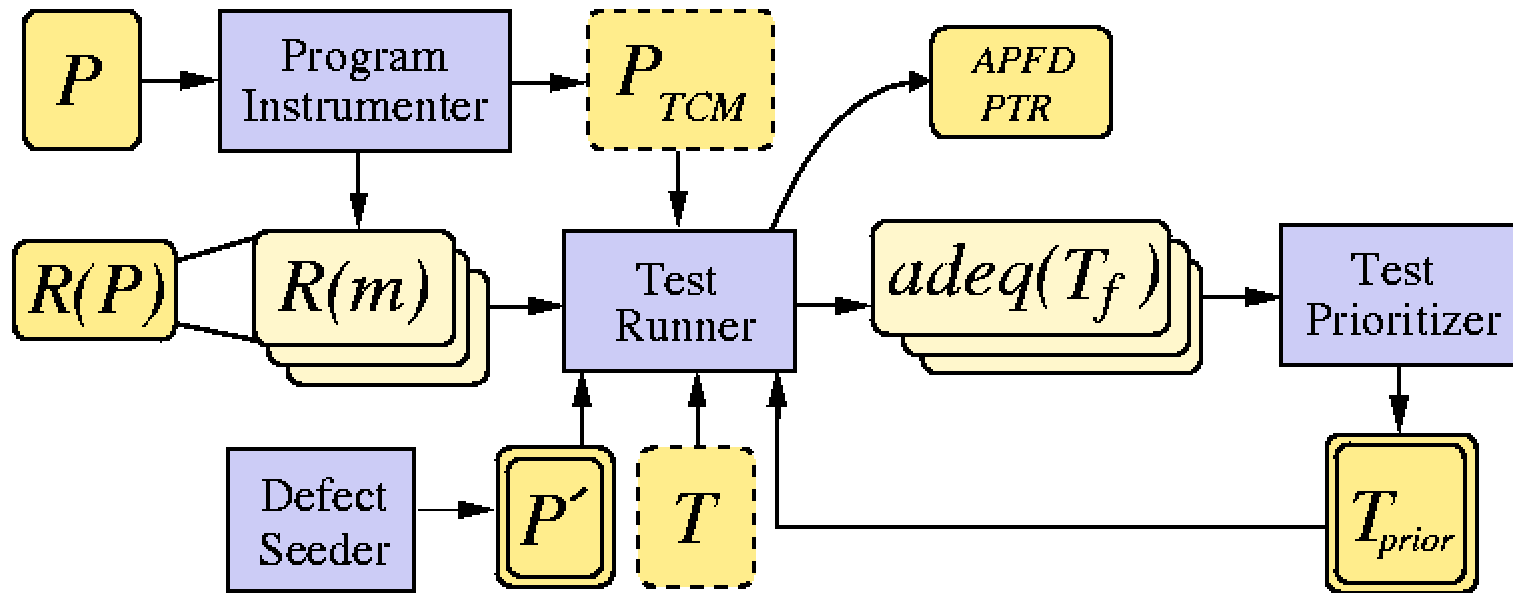
Test Case	Faults				
	$f_1$	$f_2$	$f_3$	$f_4$	$f_5$
$T_1$			×	×	
$T_2$	×	×			
$T_3$	×	×	×		
$T_4$			×	×	×
$T_5$		×	×		

$$\sigma_1 = \langle T_1, T_2, T_3, T_4, T_5 \rangle \quad \sigma_2 = \langle T_3, T_4, T_1, T_2, T_5 \rangle$$

- $APFD(T_1, P) = 1 - .4 + .1 = .7$
- $PTR(T_1, P) = \frac{4}{5}$
- $APFD(T_2, P) = 1 - .2 + .1 = .9$
- $PTR(T_2, P) = \frac{2}{5}$



## Experiment Design



### *Instrument and Enumerate*

- Calculate the set of test requirements for program  $P$
- Introduce test coverage monitoring instrumentation
- Execute test suites and report  $APFD$  and  $PTR$  calculations



## Cumulative Adequacy of a Test Case

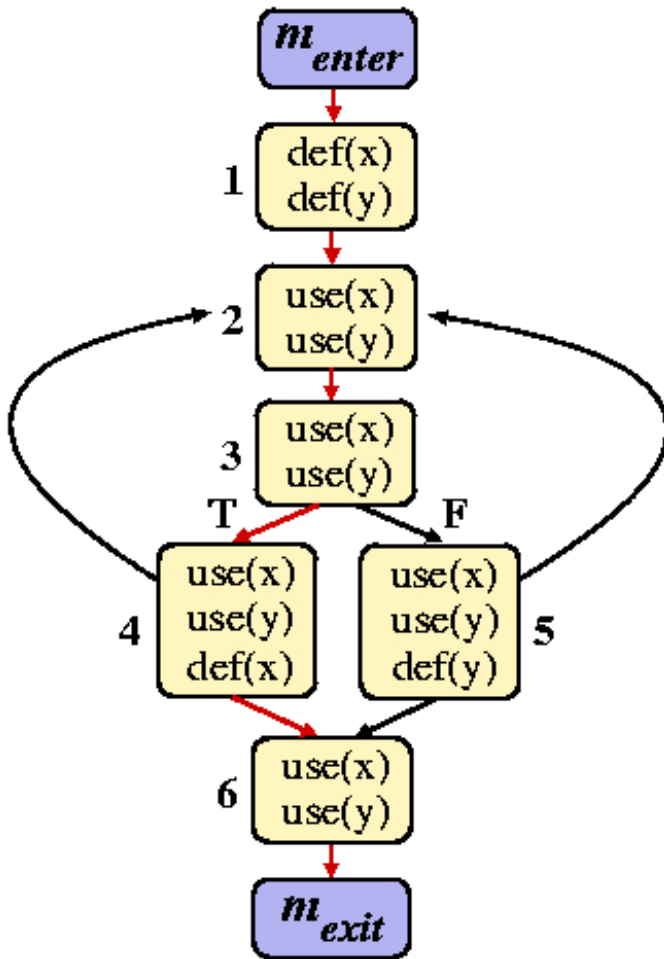
- When a test case has covered both a *def* and corresponding *use* statement, the coverage of that association is stored
- **Test case adequacy** – The ratio between the number of covered test requirements and the total number of test requirements for all of the methods under test

$$adeq(T_f) = \frac{\sum_{k=1}^h |R_c(m_k)|}{\sum_{k=1}^h |R(m_k)|}$$





# Cumulative Adequacy Example



- Model each method in a program as a control flow graph
- $T_f$  enters method  $m$  and executes the **true** branch of node 3

$$adeq(T_f) = \frac{7}{16} = 43.75\%$$



## Experimentation Statistics

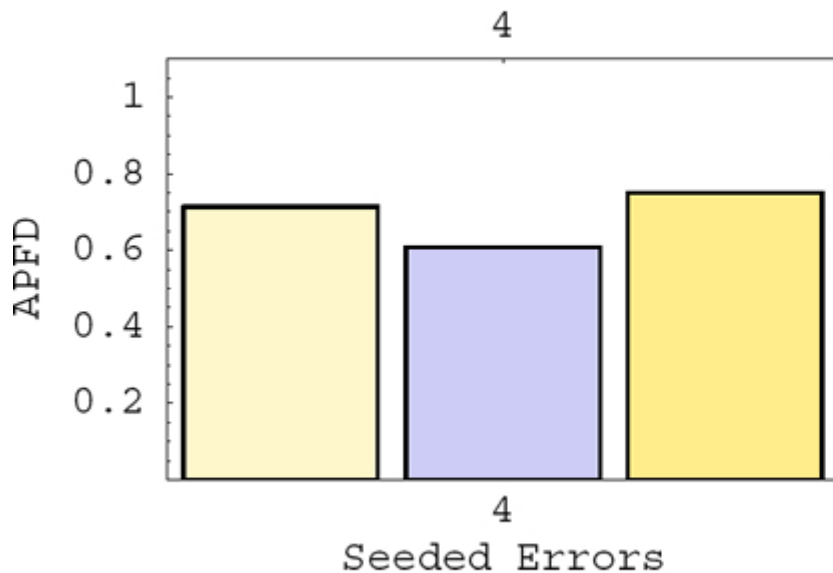
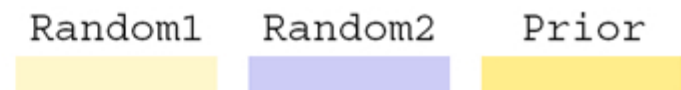
- Experiments conducted on a GNU/Linux workstation with dual 1GHz Pentium III Xeon processors, 512 MB of main memory

Case study applications:

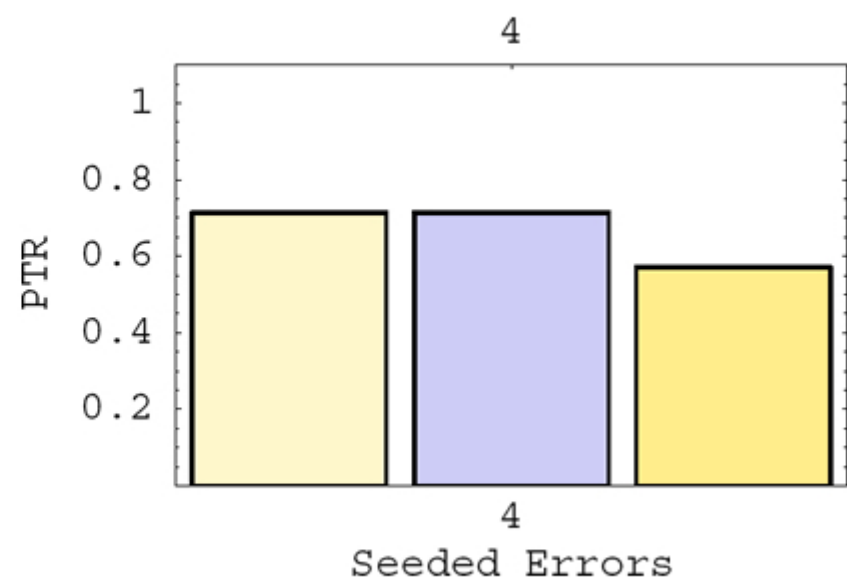
- **Bank** – 1 class, 53 def-use associations, 5 methods, 7 test cases, 4 seeded errors
- **Identifier** – 3 classes, 81 def-use associations, 13 methods, 11 test cases, 2 sets of 3 seeded errors
- **Money** – 3 classes, 302 def-use associations, 33 methods, 21 test cases, 3 sets of 3 seeded errors



## Bank *APFD* and *PTR* Measurements



**Bank *APFD***

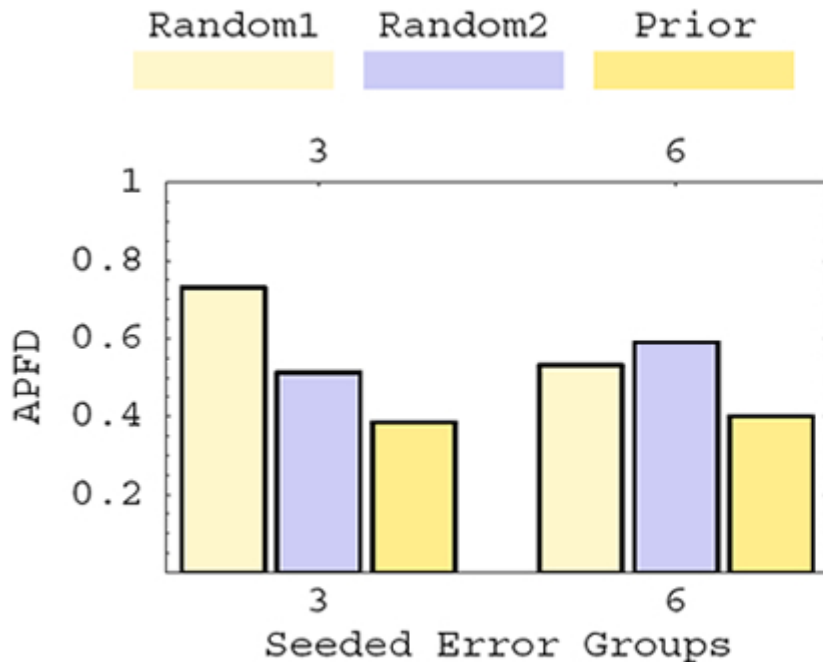


**Bank *PTR***

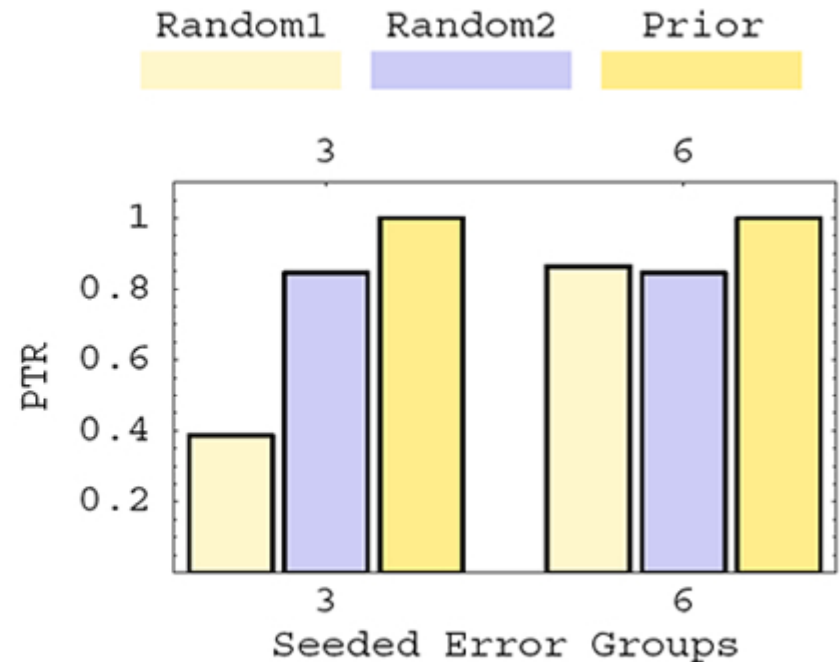
- Prioritized suite has best *PTR* value
- Prioritized suite has the best *APFD* value, slightly better than Random1



# Identifier *APFD* and *PTR* Measurements



**Identifier *APFD***

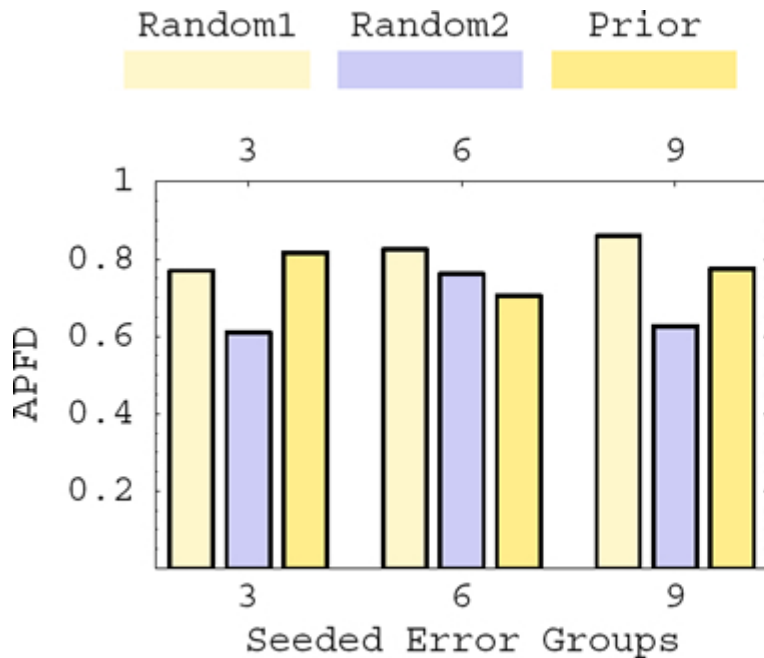


**Identifier *PTR***

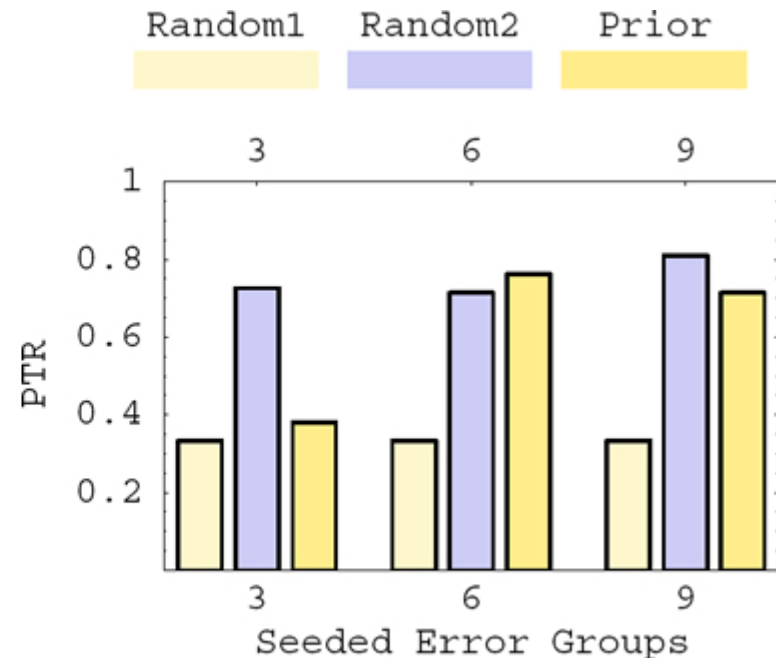
- Prioritized suite has the worst *PTR* value
- Prioritized suite has the worst *APFD* value



# Money *APFD* and *PTR* Measurements



**Money *APFD***



**Money *PTR***

- Prioritized suite has best *APFD* for 3 errors, worst for 6 errors, medium for 9 errors
- Prioritized suite has medium *APFD* for 3 errors, slightly worse than Random1, worst for 6 errors, medium for 9 errors



## Time and Memory Requirements

Program	Time (ms)	Space (bytes)
Bank	3,210	1,084,648
Identifier	3,351	2,170,871
Money	9,176	4,984,648

Time and Memory for *InsturmentandEnumerate* Algorithm

- Test case monitoring did not cause significant increases in the time required to execute test cases



## Conclusions

- Test suites can be prioritized according to *all-DUs* with minimal time and space overhead
- Preliminary results indicate that data flow-based prioritizations are not always more effective than random prioritizations
- Successfully created a low-overhead framework for performing test prioritization which can be used in future studies



## Future Work

- Incorporation of control flow-based and mutation-based adequacy into **Kanonizo**
- The comparison of our prioritization approach to other prioritization schemes beyond random
- The calculation of *APFD* and *PTR* for all permutations of an application's test suite
- Experimentation with additional case studies that have larger program segments and test suites
- The investigation of prioritization techniques for test suites that must be executed within a specified time constraint





## Related Work

- Sebastian Elbaum et al. Prioritizing test cases for regression testing. *Proceedings of the International Symposium on Software Testing and Analysis*. ACM Press, August 2000.
- Phyllis G. Frankl et al. An applicable family of data flow testing criteria. *IEEE Transactions on Software Engineering*, October 1988.
- G. Rothermel et al. A framework for evaluating regression test selection techniques. Proceedings of the 16<sup>th</sup> International Conference on Software Engineering, *IEEE Computer Society Press*, May 1994.



## Resources

- Kanonizo Research Group:  
<http://cs.allegheny.edu/~gkapfham/research/kanonizo>.
- Gregory M. Kapfhammer *The Computer Science Handbook* Chapter “Software Testing”. CRC Press, June 2004.
- Matthew Rummel, Greg Kapfhammer, and Andrew Thall  
Towards the Prioritization of Regression Test Suites with  
Data Flow Information. *Proceedings of the ACM SIGAPP  
Symposium on Applied Computing*, Santa Fe, New  
Mexico, March 2005.